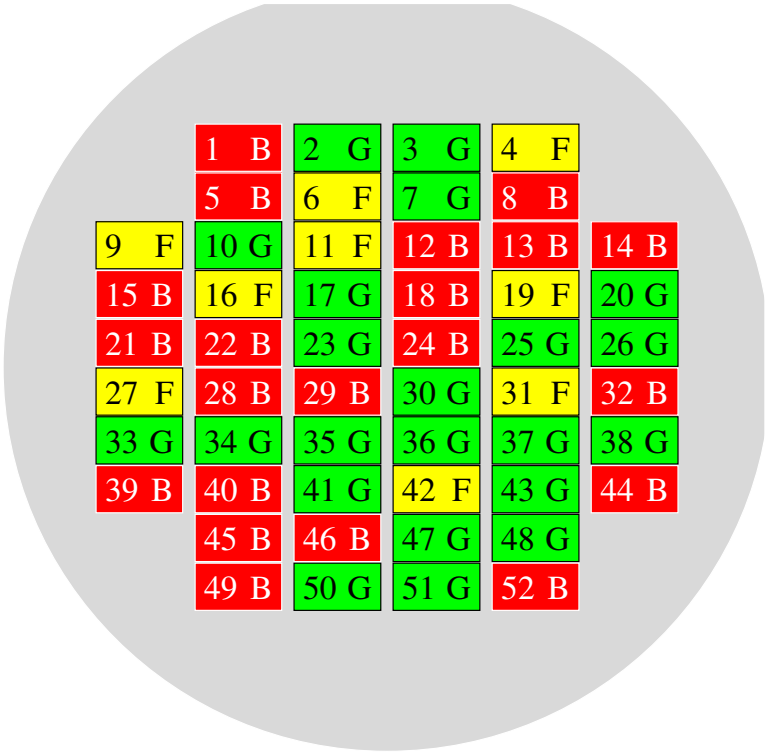
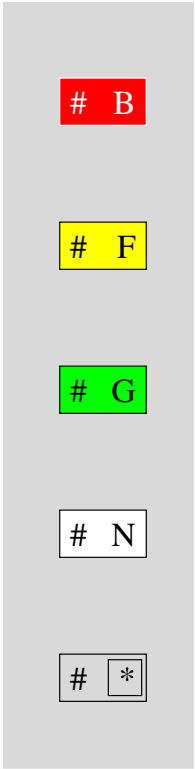
Die quality map for wafer 65 s/n: 21316-07-09

Date: 01/05/99





Bad die

Fair die

Good die

No info

Manually tagged